

[54] ELECTRONIC SYSTEM TEST INSTRUMENT

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[**] Term: 14 Years

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[52] U.S. Cl. D10/75; D14/106

[58] Field of Search D10/46, 75, 78; D14/105, 106, 100, 107; D18/7, 6, 4; 324/57, 115, 73 R, 156

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Electronic Technician/Dealer-1/75, p. 42-Multimeter at top.

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[57] CLAIM

The ornamental design for an electronic system test instrument, as shown and described.

DESCRIPTION

FIG. 1 is a top and right front perspective view of an electronic system test instrument showing my new design;

FIG. 2 is a front elevational view thereof;

FIG. 3 is a left side elevational view thereof;

FIG. 4 is a right side elevational view thereof;

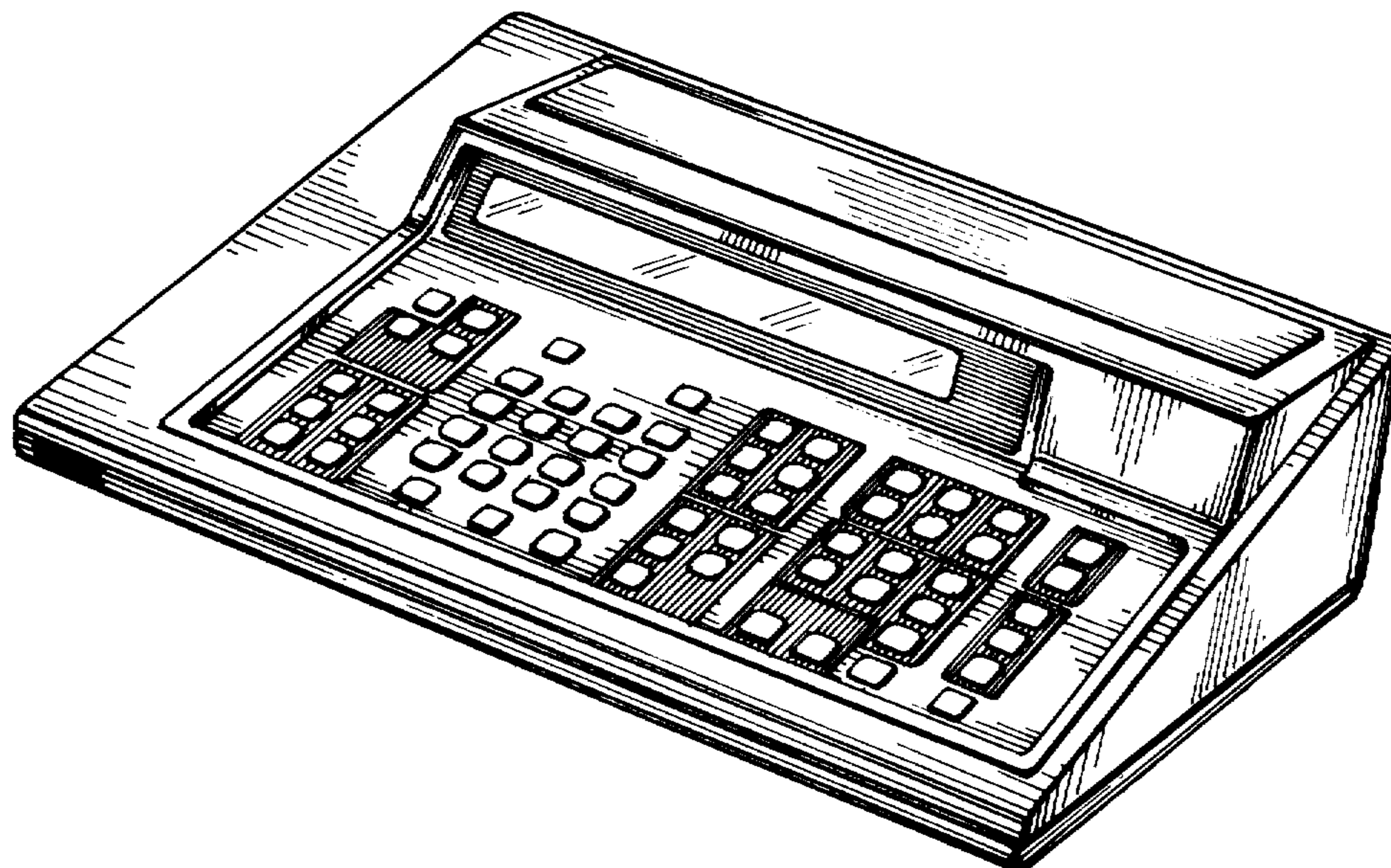
FIG. 5 is a top plan view thereof;

FIG. 6 is a bottom plan view thereof;

FIG. 7 is a left front perspective view of a second embodiment of my new design of FIGS. 1-6;

FIG. 8 is a left front perspective view of a third embodiment of my new design of FIGS. 1-6;

FIG. 9 is a left side perspective view of a fourth embodiment of my new design of FIGS. 1-6.



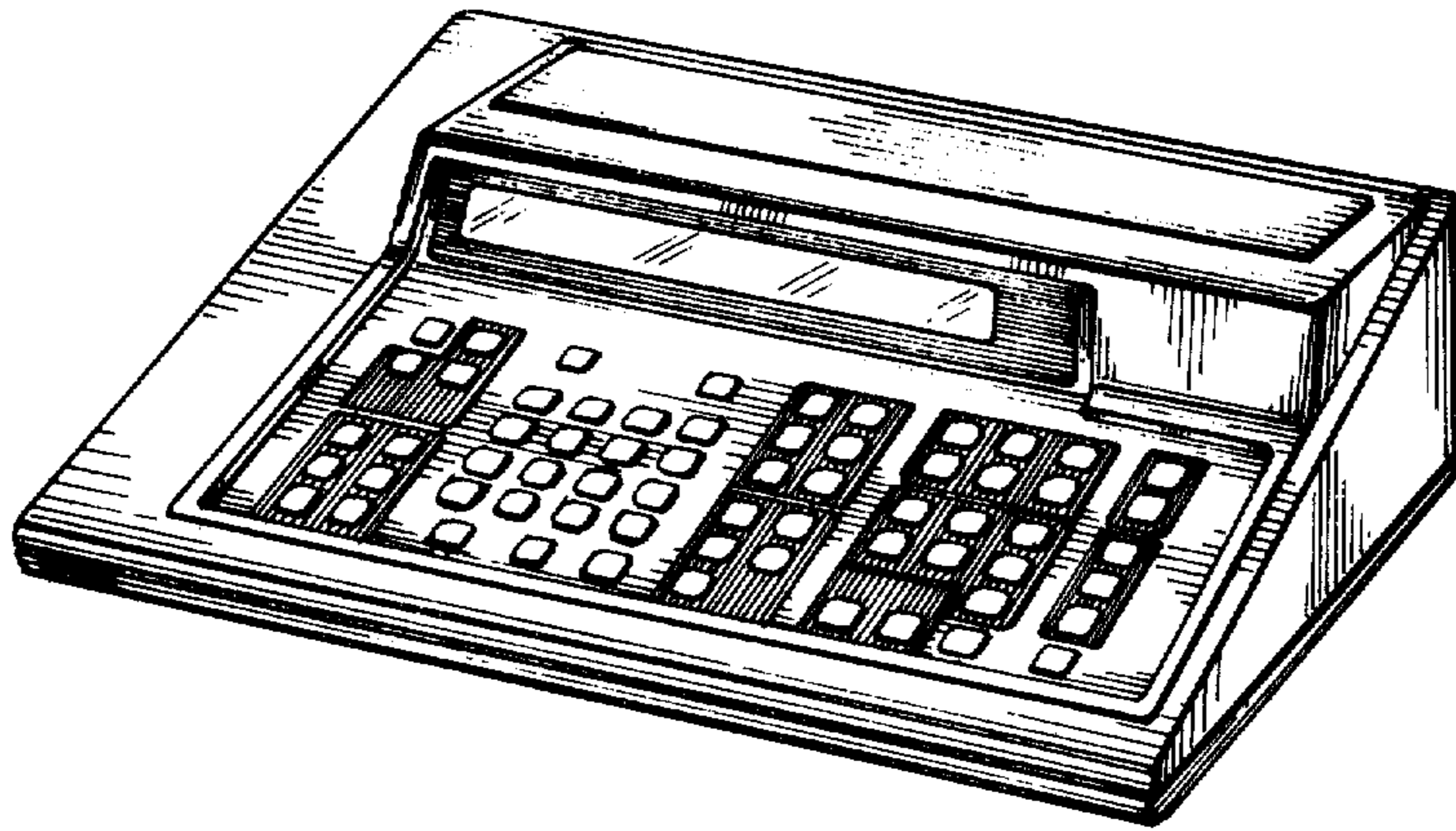


Fig. 1.

Fig. 2.

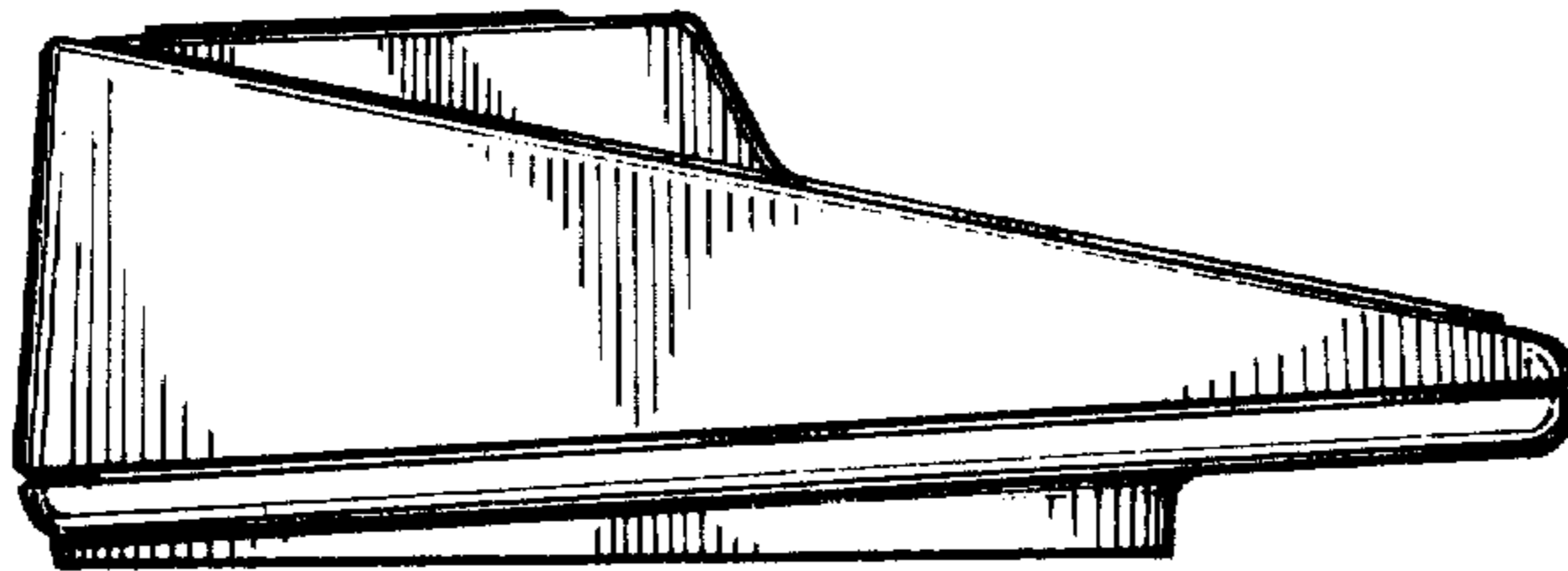
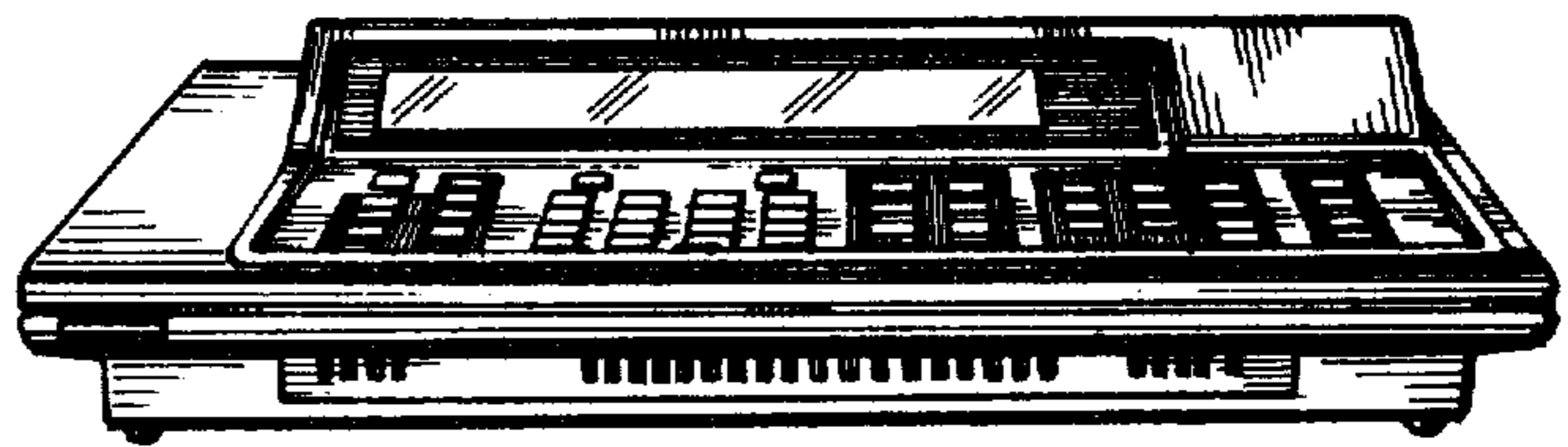
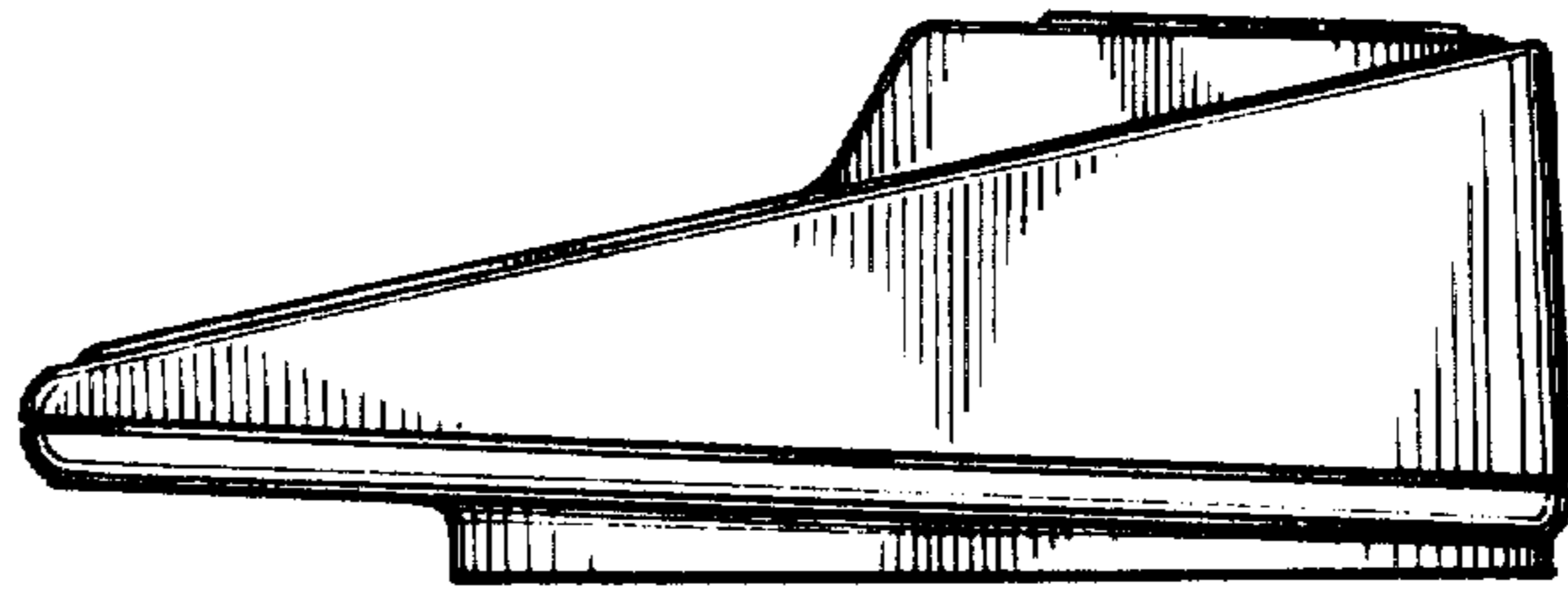


Fig. 3.

Fig. 4.



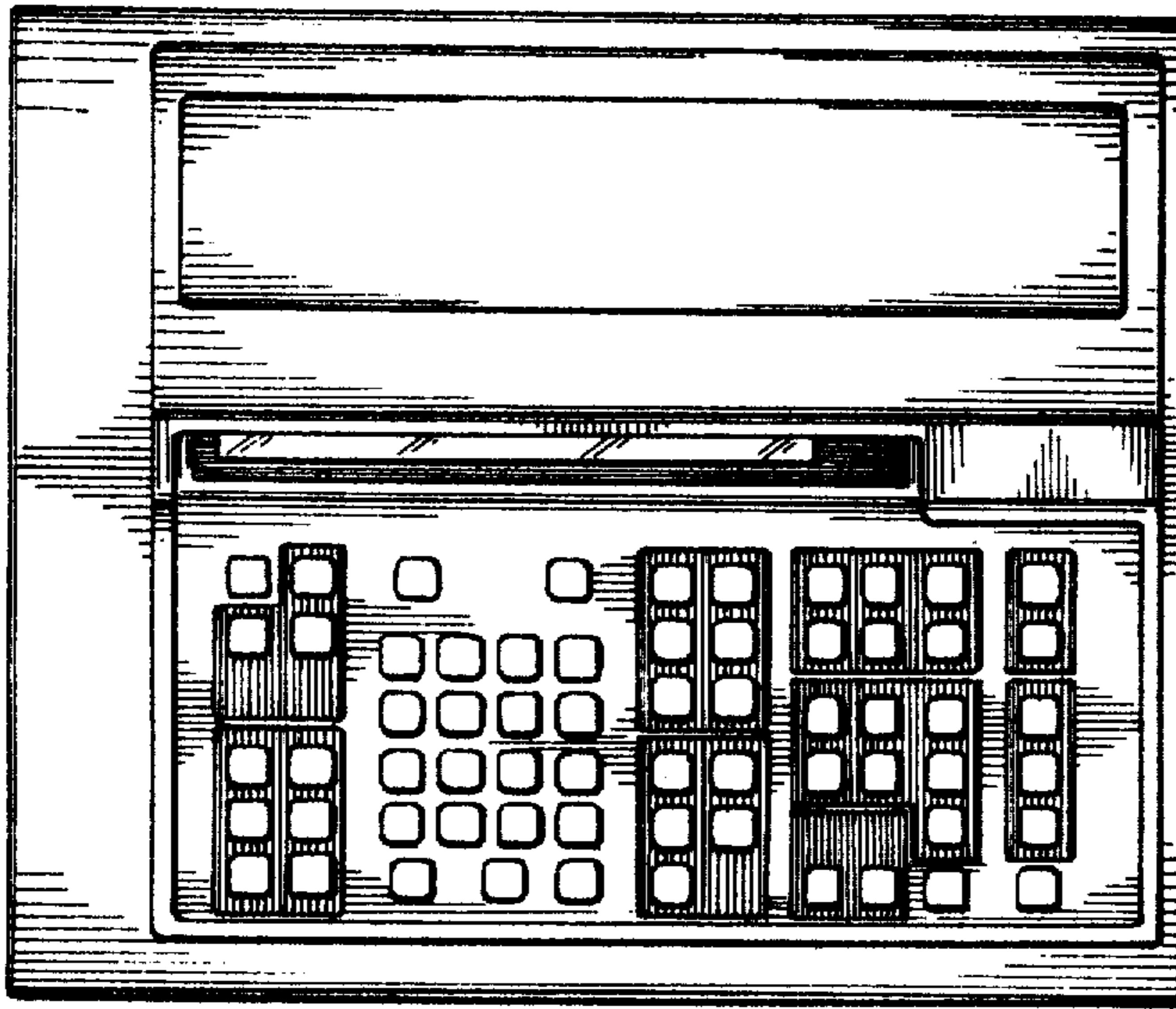


Fig. 5.

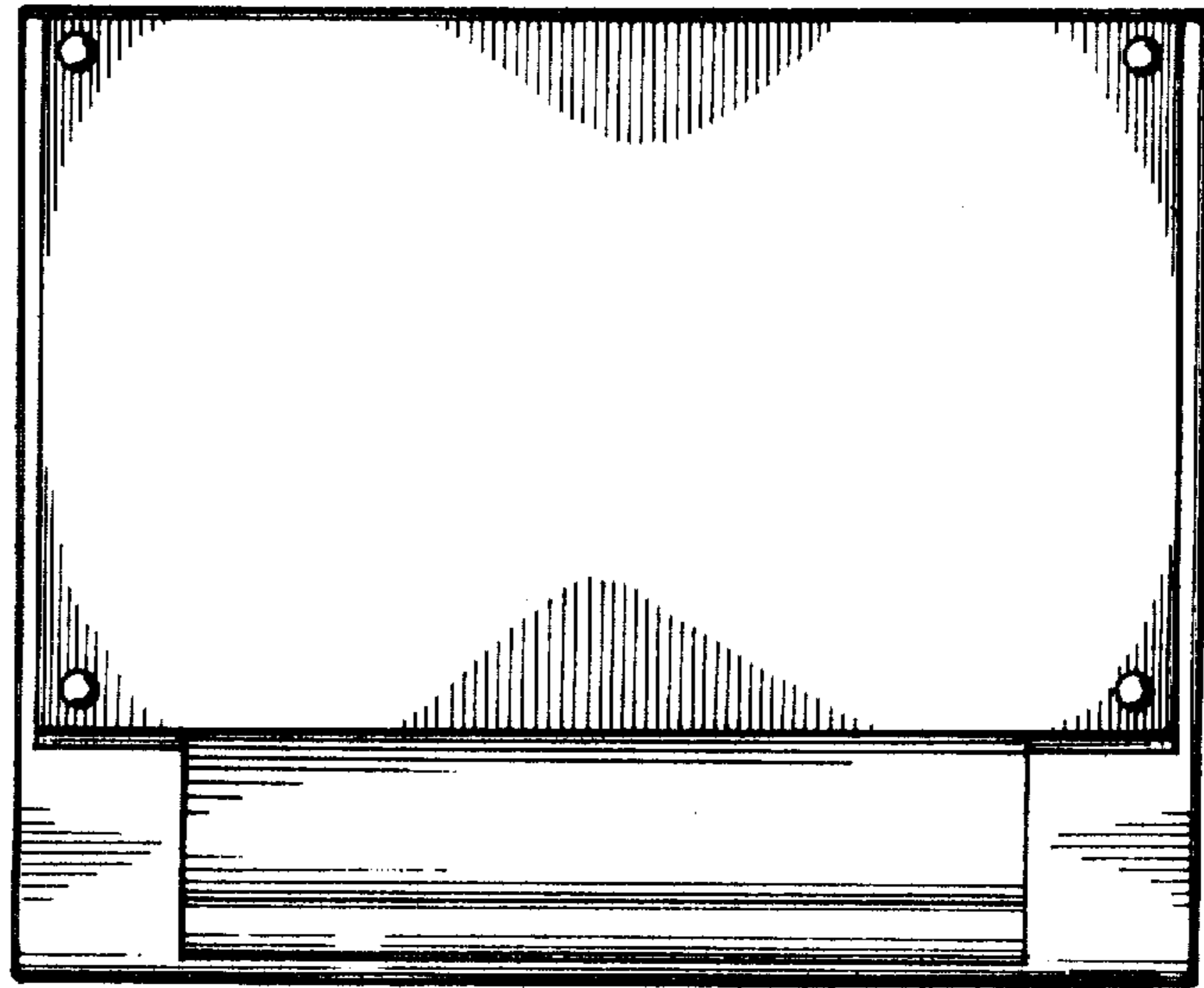


Fig. 6.

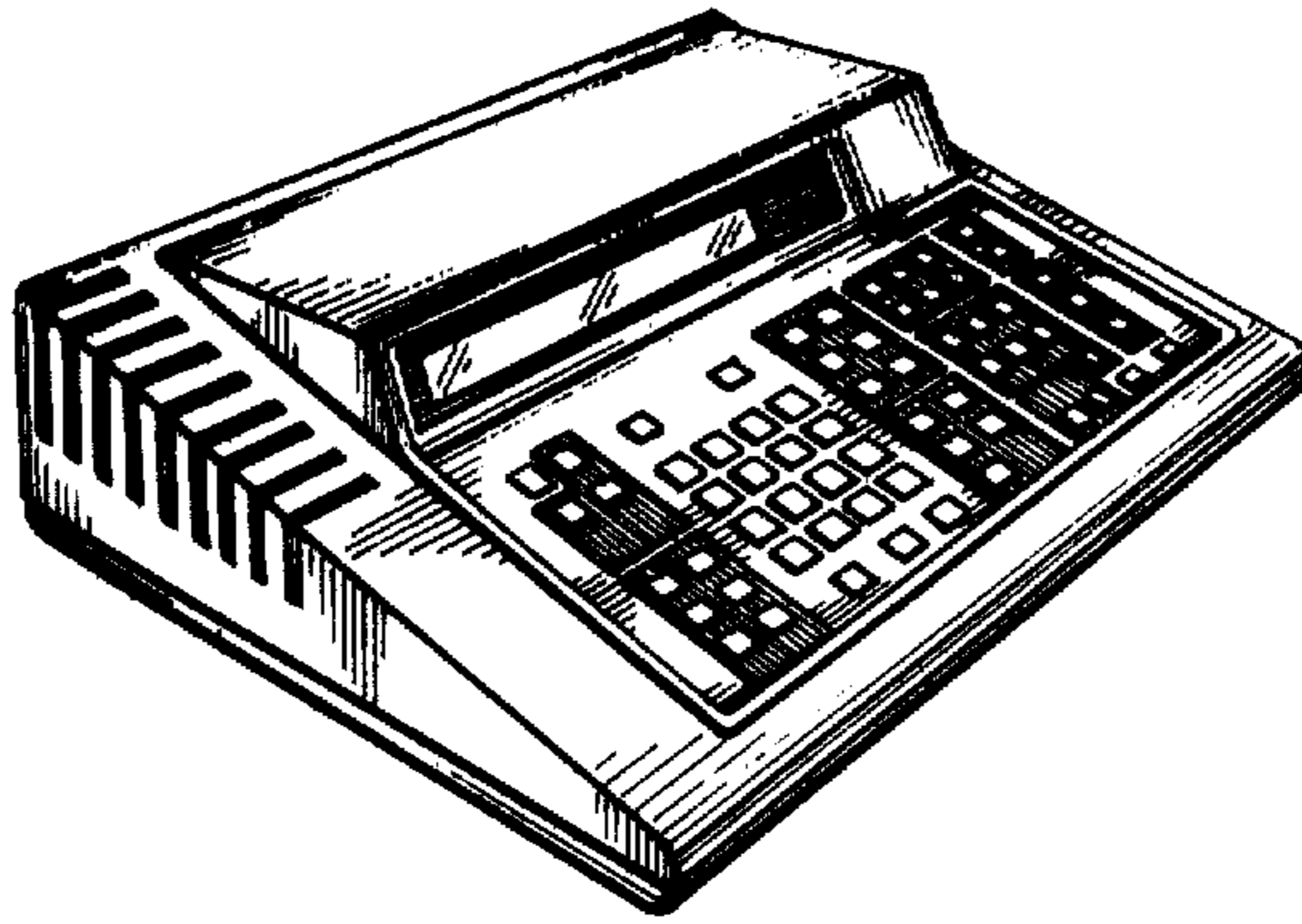


Fig. 7.

Fig. 8.

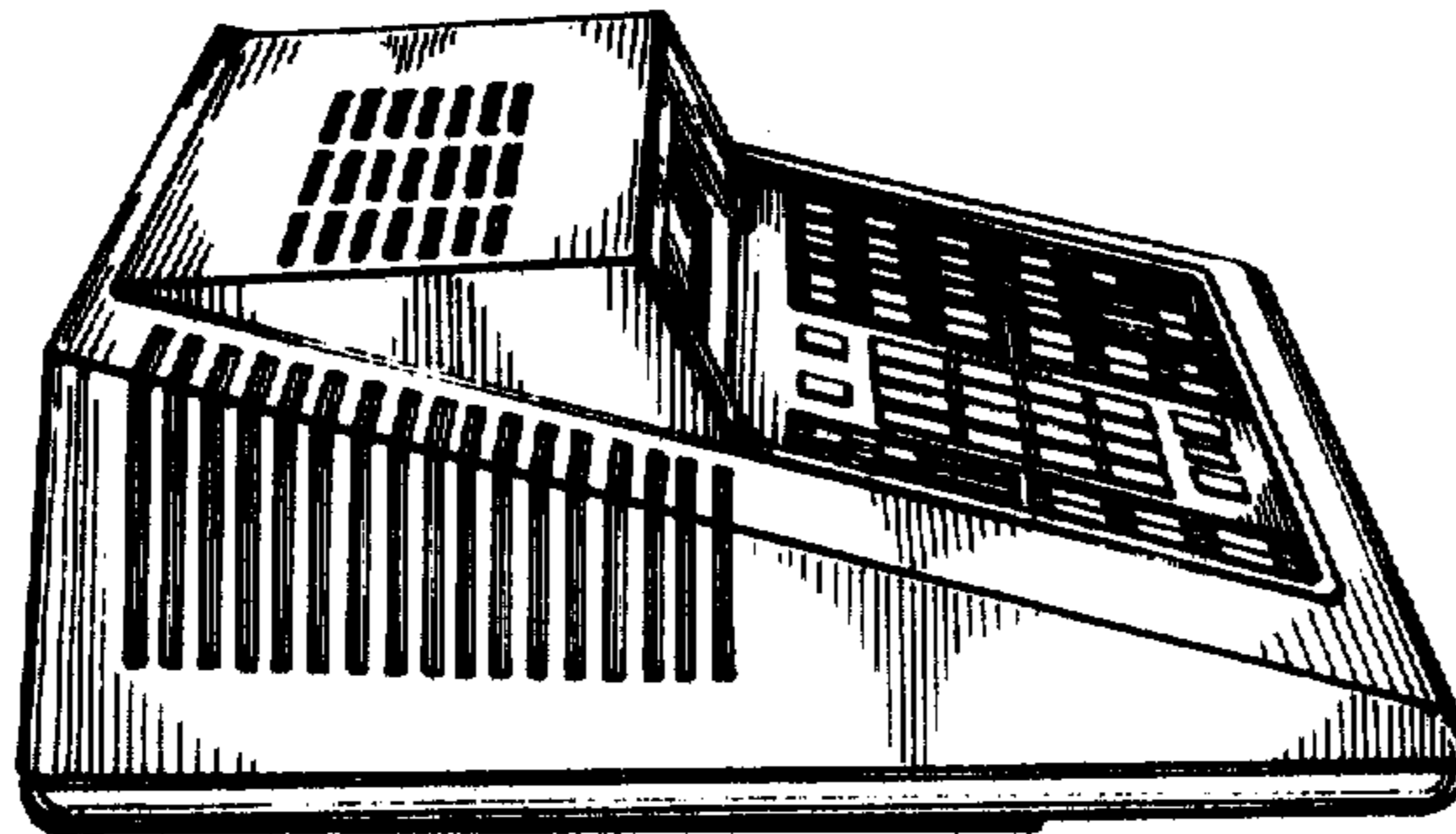
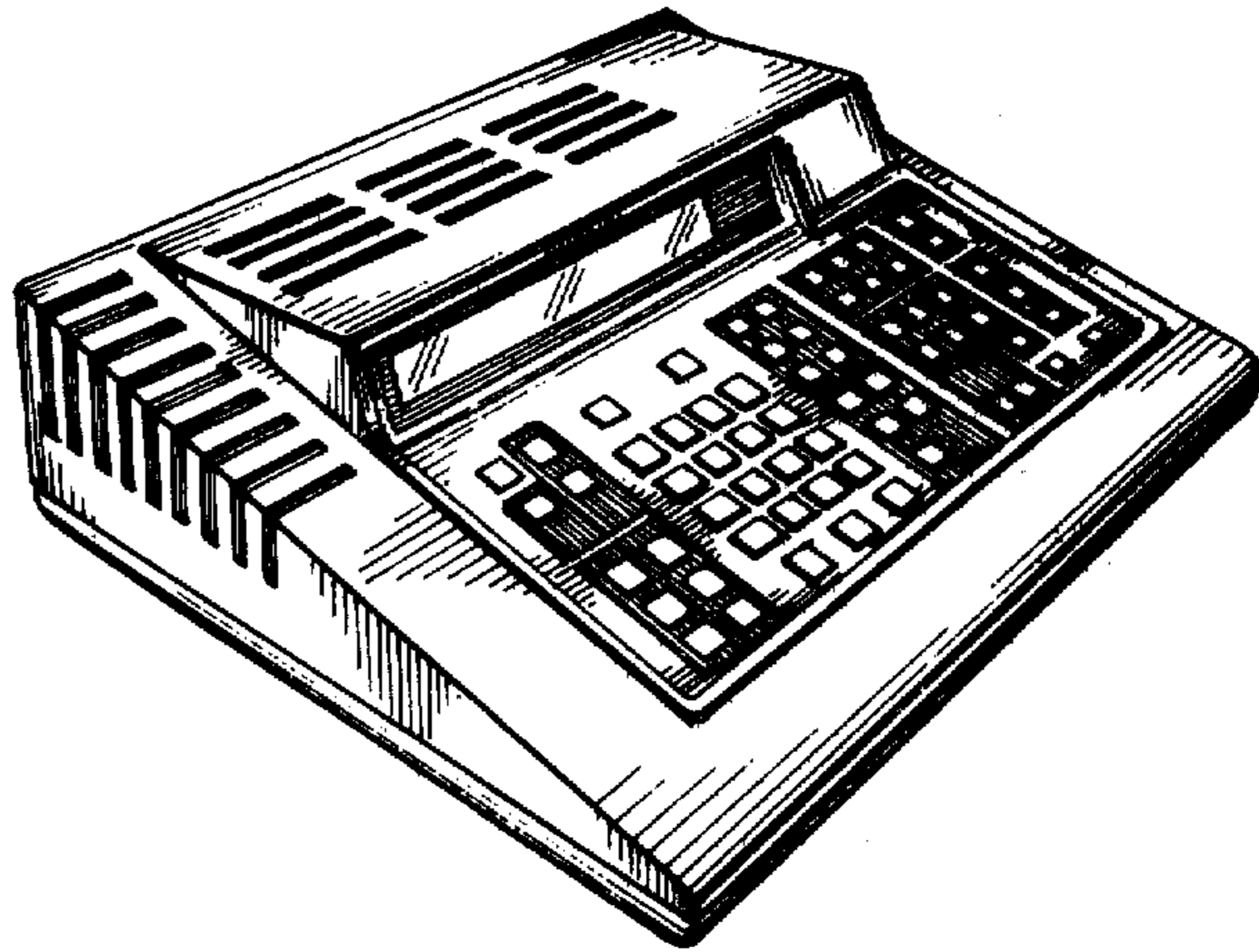


Fig. 9.